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1	INZZ	(automatic OR intelligent OR computerized) ADJ (door OR entry)	unrestricted	41	show titles
2	INZZ	self ADJ diagnosis	unrestricted	471	show titles
3	INZZ	1 AND 2	unrestricted	0	-
4	INZZ	(central OR remote) ADJ (management OR managerial OR administrative)	unrestricted	367	show titles
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- ☒ Classification codes A: Physics, 7
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-  Publication types
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1 Automatic door opener
Pik-Yiu Chan; Enderle, J.D.;

 Bioengineering Conference, 2000. Proceedings of the IEEE 26th Annual Northeast, 8-9 April 2000
 Pages:139 - 140

[\[Abstract\]](#) [\[PDF Full-Text \(160 KB\)\]](#) **IEEE CNF**
2 A habituation, rehabilitation, and recovery chip
Goru, V.K.; Akers, L.A.;

 Circuits and Systems, 1996. ISCAS '96., 'Connecting the World', 1996 IEEE International Symposium on, Volume: 3, 12-15 May 1996
 Pages:487 - 490 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(324 KB\)\]](#) **IEEE CNF**
3 Wheelchair assist devices
Chanchavac, S.; Jain, A.; Pham, D.; Pruehsner, W.; Enderle, J.D.;

 Bioengineering Conference, 2001. Proceedings of the IEEE 27th Annual Northeast, 31 March-1 April 2001
 Pages:97 - 98

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(automatic <phrase> c In: All Fields

And

In: All Fields

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